Characterization of defects in ultrafine-grained interstitial-free steel prepared by severe plastic deformation



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Ultra fine grained (UFG) materials



polycrystalline material

 $f_{GB} = 1 - \left(\frac{d - \delta}{d}\right)^3$

Ultra fine grained (UFG) materials

polycrystalline material



crystallographic width of GB's: $\delta \approx 1 \text{ nm}$

volume fraction of GB's

$$f_{GB} = 1 - \left(\frac{d - \delta}{d}\right)^3$$



Ultra fine grained (UFG) materials

polycrystalline material



Severe plastic deformation

- plastic deformation \rightarrow grain refinement
- conventional plastic deformation



Severe plastic deformation

- plastic deformation \rightarrow grain refinement
- conventional plastic deformation \rightarrow formation of cracks





Severe plastic deformation

- plastic deformation \rightarrow grain refinement
- conventional plastic deformation \rightarrow formation of cracks \rightarrow material failure





• deformation under **high pressure** \rightarrow crack formation suppressed

High pressure torsion (HPT)

- the strongest grain refinement
- grain size $\approx 100 \text{ nm}$
- disk shaped samples diameter 10 – 20 mm, thickness 0.3 - 0.5 mm



UFG IF steel sample prepared by HPT

 dislocation density is an important parameter of UFG materials



R.Z. Valiev, Nature Materials 3, 511-516 (2004)

• TEM

- direct observation of dislocations



• TEM

- direct observation of dislocations
- hard to resolve individual dislocations due to high dislocation density



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• X-ray diffraction (XRD)

- broadening of XRD profiles
- crystallite size & microstrain broadening





• X-ray diffraction (XRD)

- broadening of XRD profiles
- crystallite size & microstrain broadening
- different dependence on scattering angle



G. Ribárik et al. Mater. Sci. Eng. A 387-389, 343 (2004)

• Williamson-Hall (W-H) method

G.K. Williamson, W.H. Hall , Acta Metall. 1, 22 (1953)

- size broadening \rightarrow independent on θ
- strain broadening \rightarrow proportional to sin θ

• Williamson-Hall (W-H) method

G.K. Williamson, W.H. Hall , Acta Metall. 1, 22 (1953)

- *hkl* peak width: $\Delta K = 2\Delta \theta_{hkl} \cos \theta_{hkl} / \lambda$
- magnitude of diffraction vector: $K = 2 \sin \theta_{hkl} / \lambda$



W-H plot



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HPT deformed IF steel

modified Williamson-Hall (W-H) method

T. Ungár, A. Borbély, Appl. Phys. Lett. 69, 3173, (1996)

- *hkl* peak width: $\Delta K = 2\Delta \theta_{hkl} \cos \theta_{hkl} / \lambda$
- magnitude of diffraction vector: $K = 2 \sin \theta_{hkl} / \lambda$

$$\Delta K = \frac{0.9}{D} + bM \sqrt{\frac{\pi}{2}\rho} \left(K\overline{C}^{1/2} \right)$$

dislocation distribution parameter

dislocation contrast factor

$$\overline{C} = \overline{C}_{h00} \left(1 - qH^2 \right)$$

$$H^2 = \frac{h^2 l^2 + h^2 k^2 + l^2 k^2}{\left(h^2 + k^2 + l^2\right)^2}$$
edge



HPT deformed IF steel

fraction of screw dislocations:

$$f_{screw} = \frac{q - q_{edge}}{q_{screw} - q_{edge}}$$

edge / screw character of dislocations

dislocation contrast factor for $\{h00\}$ reflections

for common slip systems in fcc and bcc structures calculated in T. Ungár et al. J. Appl. Cryst 32, 992 (1999)

modified Williamson-Hall (W-H) method

linearization of relation

$$\frac{\left(\Delta K - \alpha\right)^2}{K^2} = \beta^2 \overline{C}_{h00} \left(1 - qH^2\right)$$

gives parameters:

$$\alpha = \frac{0.9}{D} \quad \text{(crystallite size)}$$

$$\beta = bM \sqrt{\frac{\pi}{2}} \rho$$
 (dislocation density)

q (screw / edge character of dislocations)



HPT deformed IF steel

dislocation distribution parameter M



dislocation distribution parameter M



modified Warren-Averbach (MWA) method

T. Ungár, A. Borbély, Appl. Phys. Lett. 69, 3173, (1996)

Fourier transform of XRD profiles

 $A(L) = A_{S}(L)A_{D}(L)$

size coefficient distortion coefficient

$$A_D(L) = \exp\left(-\frac{\pi}{2}b^2K^2\overline{C}\rho L^2f(\eta)\right)$$

 $\eta = \frac{1}{2} \exp\left(\frac{7}{4}\right) \frac{L}{M} \sqrt{\rho}$

strain (Wilkens) function describes dislocation-dislocation correlation



strain function

2

η

1

3

4

5

f (ŋ)

3

2

1

0

whole profile fitting

G. Ribárik, T. Ungár, J. Gubicza, J. Appl. Cryst. 34, 669, (2001)

by self consistent MWH + MWA approach one gets:

- 1. mean crystallite size D
- 2. mean dislocation density ρ
- 3. screw / edge character of dislocations *q*
- 4. dislocation distribution parameter *M*



G. Ribárik, T. Ungár, J. Gubicza: Multiple Whole Profile fitting program MWP-fit, http://csendes.elte.hu/mwp/

Positron trapping at dislocations

- dislocation line is a shallow positron trap
- weak positron localization at dislocation \rightarrow diffusion along dislocation line
- final trapping at vacancy bound to dislocation or open volume at jog

edge dislocation

screw dislocation





Positron trapping at dislocations

- two-step positron trapping at dislocation
 - $K_v \ll K_{dl}$ (vacancy is a point defect but dislocation is a line defect)

 $\delta_{dl} << K_{dv}$ (there is always enough vacancies attached to dislocation)



L.C. Smedskjaer et al., J. Phys. F 10, 2237, (1980)

Positron trapping at dislocations

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- open volumes attached to edge dislocations are larger Y.K. Park et al. , PRB 34, 823 (1986)
- screw and edge dislocations can be distinguished





- open volumes attached to edge dislocations are larger Y.K. Park et al., PRB 34, 823 (1986)
- screw and edge dislocations can be distinguished
- fraction of screw dislocations: f_{screw}

$$r = \frac{\tau_{edge}}{\tau_{screw} - \tau_{edge}}$$

 $\tau - \tau$





- open volumes attached to edge dislocations are larger Y.K. Park et al., PRB 34, 823 (1986)
- screw and edge dislocations can be distinguished
- typical lifetimes of trapped positrons in deformed steels: 150 155 ps





- open volumes attached to edge dislocations are larger Y.K. Park et al., PRB 34, 823 (1986)
- screw and edge dislocations can be distinguished
- unfortunately the lifetimes for edge and screw dislocations have been determined only for Fe so far





Positron trapping at dislocations – distribution of dislocations

- uniform distribution of dislocations \rightarrow simple trapping model $\rho = \frac{1}{\nu} \frac{I_2}{I_1} \left(\frac{1}{\tau_B} \frac{1}{\tau_D} \right)$ (hcp metals, metals with low SFE)
- dislocation cell structure \rightarrow diffusion trapping model (cubic metals with medium and high SFE)



specific positron trapping

rate to dislocations



HPT-deformed Mg-10wt.%Gd alloy



Positron trapping at dislocations – dislocation cell structure

- dislocation cell structure
- dislocation-free cell interiors



HPT-deformed IF steel

Positron trapping at dislocations – dislocation cell structure

- dislocation cell structure
- dislocation-free cell interiors
- distorted regions with high density of dislocations (dislocation walls)



HPT-deformed IF steel

- dislocation-free spherical cells with radius R
- surrounded by dislocation walls with thickness δ

thermalization



 $\frac{\partial n}{\partial t} = D_{+} \left(\frac{\partial^2 n}{\partial r^2} + \frac{2}{r} \frac{\partial n}{\partial r} \right) - \lambda_{B} n \quad \text{diffusion to distorted regions}$

annihilation from free state

- 2. positrons stopped inside cells
- $\left(\frac{\partial n}{\partial t}\right) = -\frac{\nu \rho \delta}{n D} n(R,t)$ boundary condition

 D_+ - positron diffusion coefficient

$$n(r,0) = \frac{1-\eta}{4/3\pi R^3}$$

initial condition

A. Dupasquier et al. PRB 48, 9235 (1993) J. Čížek et al. PRB 65, 094106 (2002)

 $\eta = \frac{(R+\delta)^3 - R^3}{(R+\delta)^3}$ volume fraction of distorted regions

- spherical grains with radius R
- distorted regions along grain boundaries with thickness δ
- positron lifetime spectrum

$$S(t) = \sum_{k}^{\infty} t_{k}^{-1} i_{k} e^{-t/t_{k}} + \tau_{d}^{-1} I_{d} e^{-t/\tau_{d}}$$

 τ_d – lifetime of positrons trapped at dislocations

 $I_d = 1 - \sum_{k=1}^{\infty} i_k$ – intensity of dislocation component

R B

 $t_{k} = \left(\tau_{B}^{-1} + \frac{\beta_{k}^{2}D_{+}}{R^{2}}\right)^{-1}$ - infinite number of "free positron" components

$$i_{k} = 3(1-\eta)\frac{\nu\rho\delta}{\eta R}\alpha_{k}\left(\frac{1}{t_{k}^{-1}-\tau_{B}^{-1}}-\frac{1}{t_{k}^{-1}-\tau_{d}^{-1}}\right)$$

A. Dupasquier et al. PRB 48, 9235 (1993)

J. Čížek et al. PRB 65, 094106 (2002)

$$\beta_k \cot \beta_k + \xi - 1 = 0$$

$$\alpha_k = \frac{2\xi}{\beta_k^2 + \xi(\xi - 1)} \qquad \xi = \frac{\nu R\rho}{\eta D_4}$$

- direct fitting of positron lifetime spectra by DTM
- from fitting we obtain the following structural parameters:
- size of cells 2R
- mean dislocation density ρ
- volume fraction of distorted regions η
- lifetime of positrons trapped at dislocations τ_d
- fraction of screw dislocations f_{screw}



- direct fitting of positron lifetime spectra by DTM
- fixed parameters
- width of distorted regions $\delta = 10 \text{ nm}$
- specific positron trapping rate to dislocations $v = 0.36 \times 10^{-4} \text{ m}^2\text{s}^{-1}$

J. Čížek et al., Phys. Stat. Sol. A 178, 651 (2000)

• bulk positron lifetime for Fe $\tau_B = 108 \text{ ps}$

F. Bečvář et al., Appl. Surf. Sci. 255, 111 (2008)

• positron diffusion coefficient for Fe $D_+ = 1.87 \text{ cm}^2 \text{ s}^{-1}$

F. Lukáč et al., J. Phys. Conf. Ser. 443, 012025 (2013)

50 nn

PAS and **XRD**

• PAS

- size of dislocation-free cells 2R
- mean dislocation density ρ
- fraction of screw dislocations f_{screw}
- open volume point defects (vacancies, vacancy clusters)

- XRD line profile analysis
- size of crystallites *D* (coherently diffracting domains)
- mean dislocation density ρ
- fraction of screw dislocations f_{screw}
- dislocation distribution parameter M
- lattice parameters

High pressure torsion (HPT)

- Interstitial-free steel Pohang Steel Company (POSCO), Korea
- composition (wt.%):
 0.0026 C, 0.096 Mn, 0.045 Al, 0.041 Ti
- number of HPT revolutions $N = \frac{1}{4}, \frac{1}{2}, 1, 3, 5$
- disk shaped samples diameter 14 mm, thickness 0.3 mm



 $= \frac{1}{\sqrt{3}} \frac{2\pi rN}{l} \stackrel{\bullet e - \text{true strain}}{\stackrel{\bullet N - \text{number of rotations}}{\stackrel{\bullet r - \text{distance from center}}{\stackrel{\bullet l - \text{sample thickness}}}$



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center half-radius r = 0 r = 3.5 mm



LT spectroscopy

Digital LT spectrometer: F. Bečvář et al., Nucl. Instr. Meth. A 539, 372 (2005)

- Two photomultipliers Hamamatsu H3378 & BaF₂ scintillators
- two 8-bit digitizers Acqiris DC211, sampling rate 4 GHz
- time resolution 145 ps (FWHM ²²Na)
- at least 10⁷ annihilation events collected in each LT spectrum
- 1 MBq ^{22}Na source deposited on 2 μm Mylar foil
- source contribution determined using well annealed Fe: $\tau_{1s} \approx 368$ ps, $I_{1s} \approx 9$ %





X-ray diffraction

XRD diffractometer:

- Double crystal diffractometer with negligible instrumental broadening
- Ge monochromator
- Co $K_{\alpha 1}$ radiation (λ =0.1789 nm)
- size of X-ray beam spot: $2 \times 0.2 \text{ mm}^2$
- linear position sensitive detector

Results of positron lifetime spectroscopy

HPT deformed IF steels

Decomposition of LT spectra into independent exponential components



Generation of vacacies during HPT



movement of dislocation with a jog

J. Čížek et al. J. Phys.: Conf. Series 443, 012008 (2013)

Generation of vacacies during SPD



vacancies agglomerate to small vacancy clusters

J. Čížek et al. J. Phys.: Conf. Series 443, 012008 (2013)

Results of positron lifetime spectroscopy

HPT deformed IF steels

Decomposition of LT spectra into independent exponential components



Results of positron lifetime spectroscopy

Ab-initio theoretical calculations

- bcc Fe
- dependence of positron lifetime on the size of vacancy clusters



Diffusion trapping model with vacancy clusters

cells contain uniformly distributed vacancy clusters



positron lifetime spectrum

$$S(t) = \sum_{k}^{\infty} t_{k}^{-1} i_{k} e^{-t/t_{k}} + \tau_{d}^{-1} I_{d} e^{-t/\tau_{d}} + \tau_{cl}^{-1} I_{cl} e^{-t/\tau_{cl}}$$

positrons trapped at vacancy clusters

J. Čížek et al. PRB 65, 094106 (2002)

Dislocation density

HPT deformed IF steel



equivalent strain

Dislocation density

- good agreement between PAS and XRD
- dislocation density increases with strain and saturates at $e \ge 3$
- edge dislocations prevail



Dislocation cell size





Dislocation cell size

- cell size is close to 100 nm already at $N = \frac{1}{4}$
- saturation at $d \approx 90$ nm
- good agreement between PAS and XRD



Electron backscatter diffraction (EBSD)

HPT deformed IF steel

 early stage of HPT processing: bimodal structure



Electron backscatter diffraction (EBSD)

- early stage of HPT processing: bimodal structure
- *N* = 5: equiaxed fine grains
- grain refinement is faster at half-radius than in the centre



Electron backscatter diffraction (EBSD)

HPT deformed IF steel

- half radius, N = 5 (e = 54)
- mean grain size $\approx 600 \text{ nm}$





grains consist of dislocation cells separated by dislocation walls
 grains

dislocation cells

TEM bright field image

20 nm



Development of mictrostructure during HPT processing



Conclusions

- Positron lifetime spectroscopy enables to determine
 - size of dislocation cells
 - mean dislocation density
 - edge or screw character of dislocations
- PAS results are consistent with results of X-ray line profile analysis
- use of PAS combined with XRD is beneficial for characterization of UFG materials
- PAS is more sensitive to dislocations than XRD
- XRD enables to determine ρ in materials containing very high number of dislocations
- PAS provides information not only about dislocations but also about open volume point defects (vacancies, vacancy clusters ...)